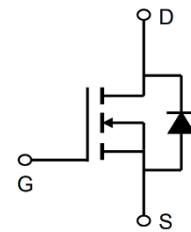


200V N-Channel Enhancement Mode MOSFET**Description**

The AP130N20P is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

**General Features**

VDS =200V, ID =130A

RDS(ON) <23mΩ@ VGS=10V

**Application**

Power amplifier

motor drive

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP130N20P	TO-247-3 Plus	AP130N20P XXX YYYY	600

Absolute Maximum Ratings $T_c = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage ($V_{GS} = 0\text{V}$)	V_{DSS}	200	V
Continuous Drain Current	I_D	130	A
Pulsed Drain Current (note1)	I_{DM}	360	A
Gate-Source Voltage	V_{GSS}	± 30	V
Single Pulse Avalanche Energy (note2)	E_{AS}	2000	mJ
Avalanche Current (note1)	I_{AR}	30	A
Repetitive Avalanche Energy (note1)	E_{AR}	25	mJ
Power Dissipation ($T_c = 25^\circ\text{C}$)	P_D	450	W
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55~+150	°C
Thermal Resistance, Junction-to-Case	R_{thJC}	0.28	°C/W
Thermal Resistance, Junction-to-Ambient	R_{thJA}	60	

200V N-Channel Enhancement Mode MOSFET

Electrical Characteristics at $T_j = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	200	--	--	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 200\text{V}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	--	--	1	μA
IGSS	Gate-Source Leakage	$V_{GS} = \pm 20\text{V}$	--	--	± 100	nA
VGS(th)	Gate-Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	3.0	4.0	V
RDS(on)	Drain-Source On-Resistance (Note3)	$V_{GS} = 10\text{V}, I_D = 45\text{A}$	--	18	23	$\text{m}\Omega$
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}, f = 1.0\text{MHz}$	--	6500	--	pF
C_{oss}	Output Capacitance		--	980	--	
C_{rss}	Reverse Transfer Capacitance		--	370	--	
Q_g	Total Gate Charge	$V_{DD} = 160\text{V}, I_D = 90\text{A}, V_{GS} = 10\text{V}$	--	200	--	nC
Q_{gs}	Gate-Source Charge		--	28	--	
Q_{gd}	Gate-Drain Charge		--	60	--	
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 100\text{V}, I_D = 90\text{A}, R_G = 25\Omega$	--	45	--	ns
t_r	Turn-on Rise Time		--	70	--	
$t_{d(off)}$	Turn-off Delay Time		--	110	--	
t_f	Turn-off Fall Time		--	90	--	
IS	Continuous Body Diode Current	$T_C = 25^\circ\text{C}$	--	--	90	A
ISM	Pulsed Diode Forward Current		--	--	360	
V_{SD}	Body Diode Voltage	$T_J = 25^\circ\text{C}, I_{SD} = 90\text{A}, V_{GS} = 0\text{V}$	--	--	1.4	V
trr	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_S = 90\text{A}, dI/dt = 100\text{A}/\mu\text{s}$	--	280	--	ns
Qrr	Reverse Recovery Charge		--	2.4	--	μC

Notes

- 1、Repetitive Rating: Pulse width limited by maximum junction temperature
- 2、 $I_{AS} = 30\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
- 3、Pulse Test: Pulse